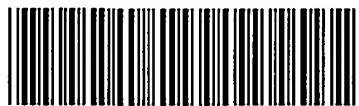


Search Notes**Application/Control No.**

10/608,914

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

AGRAWAL, AVNEESH

Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375 1	132	12/11/05	2-15 a
0	135		
375	130	9/1	
370	350		
1	341	1	
370	329		2-16
455	428		2-35
455	103	12/12/05	2-15

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
2-AS1	12/12/05	2-15

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner